

<b>Notice of References Cited</b>	Application/Control No. 10/799,714		Applicant(s)/Patent Under Reexamination MIHASHI ET AL.	
	Examiner Jeffrey D. Lane		Art Unit 2828	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-6,323,507	11-2001	Yokoyama et al.	257/79
	C	US-			
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	T	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	"Effect of Au thickness on laser beam penetration in Invar-to-Invar packages" Wang, S.C.; Chang, H.L.; Wang, C.; Wang, C.M.; Liaw, J.W.; Sheen, M.T.; Sheu, Y.C.; Kuang, J.H.; Chi, S.; Yang, Y.D.; Cheng, W.H.; Electronic Components and Technology Conference, 1997. Proceedings., 47th; 18-21 May 1997 Page(s):1272 - 1276.
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.